

本試題是否可以使用計算機:  可使用,  不可使用 (請命題老師勾選)

1. Density of states  $N(E)$  is the number of available electronic states per unit volume per unit energy around the energy  $E$ . Accounting for spin, the density of states in a three dimensional system is  $N(E) = \frac{\sqrt{2}m^{3/2}E^{1/2}}{\pi^2\hbar^3}$ . Derive  $N(E)$  in a 2-D system (as quantum well) and in a 1-D system (as quantum wire). (10%, 10%)
2. Assume an abrupt junction of n- and p- type Silicon, with the doping concentrations  $N_D 5 \times 10^{18} \text{ cm}^{-3}$  and  $N_A 2 \times 10^{15} \text{ cm}^{-3}$ . The intrinsic carrier density of Si is  $1 \times 10^{10} \text{ cm}^{-3}$  at temperature 300 K. The permittivity and dielectric constant of Si are  $\epsilon_0: 8.854 \times 10^{-12}$  (farads/meter) and 11.9. Calculate the built-in voltage and the width of the depletion region. (15%)

3. Consider two energy levels  $E_1$  and  $E_2$  of an atom, where  $E_1$  corresponds to the ground state and  $E_2$  corresponds to the excited state. Einstein identified three radiative processes expressed by

$$\frac{dn_2}{dt} = -A_{21}n_2 + B_{12}n_1\rho(\nu) - B_{21}n_2\rho(\nu) = -\frac{dn_1}{dt}$$

, where  $n_2$  and  $n_1$  are the populations of  $E_2$  and  $E_1$ . The coefficients of  $A_{21}$ ,  $B_{12}$ ,  $B_{21}$  correspond to the radiative rates of spontaneous emission, absorption and stimulated emission. By Plank formula, the electromagnetic energy density inside a cavity at the central frequency of interest  $\nu$  is

$$\rho(\nu) = \left( \frac{8\pi n^3 \nu^2}{c^3} \right) \frac{h\nu}{e^{h\nu/kT} - 1}, \text{ where } h\nu = E_2 - E_1. \text{ Using classic Boltzmann statistics}$$

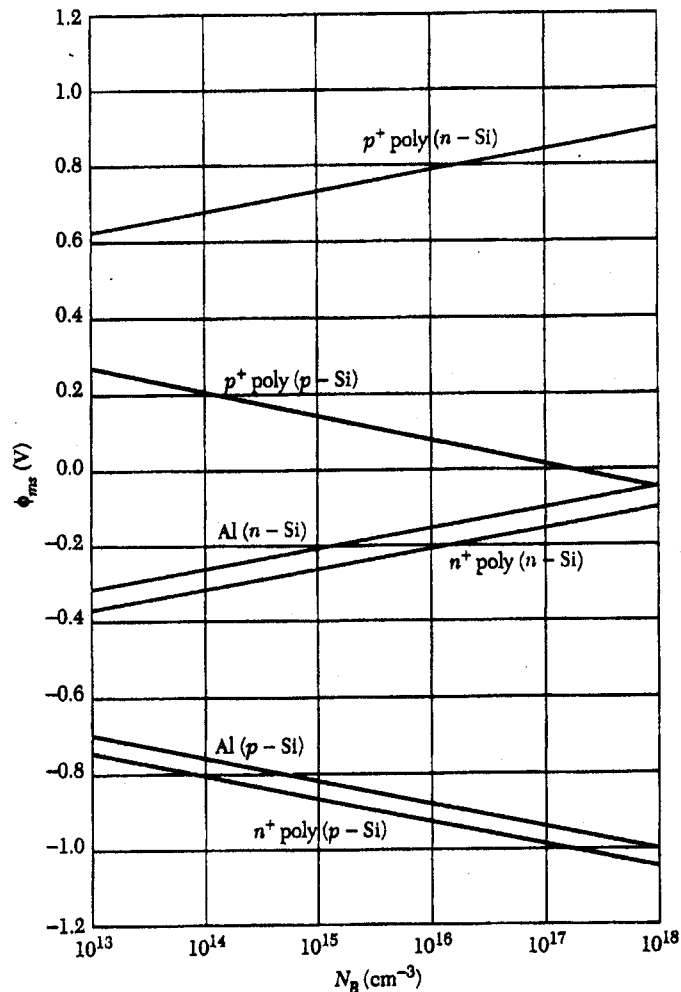
$$n_2/n_1 = \exp(-h\nu/kT), \text{ find out } \frac{A_{21}}{B_{21}} \text{ and } \frac{B_{12}}{B_{21}}. (15\%)$$

4. Germanium has bandgap  $E_g = 0.66 \text{ eV}$ , dielectric constant  $\epsilon_r = 15.8$ , and electron effective mass  $m_e = 0.1 m_0$ , where  $m_0$  is real mass of an electron. Find the donor ionization energy. (10%)
5. A heterojunction bipolar transistor (HBT) has a bandgap of 1.5 eV for the emitter and 1.35 eV for the base. A bipolar junction transistor (BJT) has a bandgap of 1.35 eV for both the emitter and base materials. The emitter doping is  $10^{17} \text{ cm}^{-3}$  and base doping is  $10^{15} \text{ cm}^{-3}$  for BJT. If the HBT has the same emitter doping and the same common-emitter current gain  $\beta_0$  as the BJT, find the base doping of HBT. Assume  $T = 300 \text{ K}$  and all other device parameters are the same. (15%)

(背面仍有題目.請繼續作答)

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6. Consider the work function difference as a function of background impurity concentration shown below. For an n-channel  $n^+$ -polysilicon-SiO<sub>2</sub>-Si MOSFET with substrate doping  $N_A = 10^{17} \text{ cm}^{-3}$  and fixed oxide charge  $Q_f/q = 4 \times 10^{11} \text{ cm}^{-2}$ , calculate the threshold voltage  $V_T$  of this device if the gate oxide thickness is 4 nm. Assume  $T = 300 \text{ K}$  and intrinsic carrier density of Si is  $10^{10} \text{ cm}^{-3}$ . (15%)



7. An n-channel GaAs MESFET has a tungsten contact. The barrier height of W-GaAs diode is 0.9 V. The n-channel doping is  $3 \times 10^{15} \text{ cm}^{-3}$  and the channel thickness is  $0.5 \mu\text{m}$ . Calculate the pinch-off voltage of this MESFET. Assume  $T = 300 \text{ K}$  and the dielectric constant of GaAs is 12.4. (10%)